



PATENT

-1-

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Jeffrey T. Fanton et al.

Application No.: 10/053,373

Filed: October 24, 2001

For: X-RAY REFLECTANCE
MEASUREMENT SYSTEM WITH
ADJUSTABLE RESOLUTION

Group No.: 2882

Examiner: I. Kiknadze

ASSOCIATE POWER OF ATTORNEY

121 Spear Street, Suite 290
San Francisco, CA 94105
Telephone: 415-512-1312
Facsimile: 415-512-1362

M/S NON-FEE AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited
with the United States Postal Service as First Class Mail in an
envelope, addressed to: Commissioner for Patents, P.O.
Box 1450, Alexandria, VA 22313-1450 on Oct. 2, 2003.

STALLMAN & POLLOCK LLP

Dated: 10/2/2003

By:

Georgia K. Stith
Georgia K. Stith

Sir:

Please recognize as Associate Patent Attorney in this case:

Name of Attorney: Jason D. Lohr

Address: 121 Spear Street, Suite 290
San Francisco, CA 94111

Reg. No.: 48,163

Telephone: (415) 512-1312

RECEIVED
OCT - 9 2003
TECHNOLOGY CENTER 2800

Signature of Principal Attorney of Record

Date: October 1, 2003

By:

Michael A. Stallman (Reg. No. 29,444)

Attorneys for Applicant(s)